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	3LL3	$527 \Pi = MARC$	CH 1997 – REVISED
<ul> <li>4:28 Data Channel Compression at up to 238 MBytes/s Throughput</li> </ul>		G PACKAG	
<ul> <li>Suited for SVGA, XGA, or SXGA Display Data Transmission From Controller to Display With Very Low EMI</li> </ul>	V <sub>CC</sub> [ D5 [ D6 [	2 55	] D4 ] D3 ] D2
<ul> <li>28 Data Channels and Clock-In Low-Voltage TTL</li> </ul>	GND	5 52	] GND ] D1
<ul> <li>4 Data Channels and Clock-Out Low-Voltage Differential</li> </ul>	D8 [ D9 [	7 50	] D0 ] D27
<ul> <li>Operates From a Single 3.3-V Supply With 250 mW (Typ)</li> </ul>	~~ <b>¬</b>	9 48	LVDSGND Y0M
<ul> <li>ESD Protection Exceeds 6 kV</li> <li>5-V Tolerant Data Inputs</li> </ul>	D12	11 46	] Y0P ] Y1M
<ul> <li>Selectable Rising or Falling Edge-Triggered Inputs</li> </ul>	D13 [ GND [ D14 [	13 44	] Y1P ] LVDSV <sub>CC</sub> ] LVDSGND
<ul> <li>Packaged in Thin Shrink Small-Outline Package With 20-Mil Terminal Pitch</li> </ul>	D15 [ D16 [	15 42	] Y2M ] Y2P
Consumes Less Than 1 mW When Disabled	CLKSEL [ D17 [		CLKOUTM
<ul> <li>Wide Phase-Lock Input Frequency Range 31 MHz to 68 MHz</li> </ul>	D18 [ D19 [		] ҮЗМ ] ҮЗР
<ul> <li>No External Components Required for PLL</li> <li>Outputs Meet or Exceed the Requirements</li> </ul>	GND	21 36	LVDSGND
of ANSI EIA/TIA-644 Standard	4	23 34	PLLGND PLLV <sub>CC</sub>
Improved Replacement for the DS90C581	D22 [ D23 [	25 32	] PLLGND ] SHTDN
description			
The SN75LVDS83 FlatLink transmitter contains four 7-bit parallel-load serial-out shift registers, a	D24 [ D25 [		] D26 ] GND

7× clock synthesizer, and five low-voltage

differential-signaling (LVDS) line drivers in a single integrated circuit. These functions allow 28 bits of single-ended low-voltage TTL (LVTTL) data to be synchronously transmitted over five balanced-pair conductors for receipt by a compatible receiver, such as the SN75LVDS82. The SN75LVDS83 can also be used in 21-bit links with the SN75LVDS86 receiver.

When transmitting, data bits D0 through D27 are each loaded into registers upon the edge of the input clock signal (CLKIN). The rising or falling edge of the clock can be selected by way of the clock select (CLKSEL) terminal. The frequency of CLKIN is multiplied seven times (7×) and then used to unload the data registers in 7-bit slices and serially. The four serial streams and a phase-locked clock (CLKOUT) are then output to LVDS output drivers. The frequency of CLKOUT is the same as the input clock, CLKIN.

The SN75LVDS83 requires no external components and little or no control. The data bus appears the same at the input to the transmitter and output of the receiver with the data transmission transparent to the user. The only user intervention is the possible use of the shutdown/clear (SHTDN) active-low input to inhibit the clock and shut off the LVDS output drivers for lower power consumption. A low-level signal on SHTDN clears all internal registers to a low level.

The SN75LVDS83 is characterized for operation over free-air temperature ranges of 0°C to 70°C.



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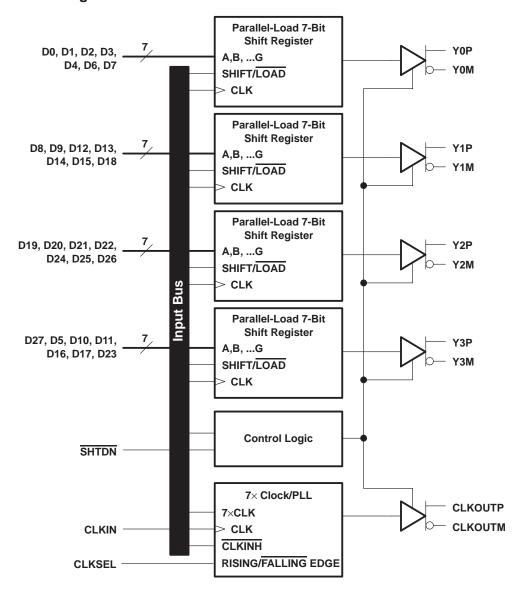
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### functional block diagram





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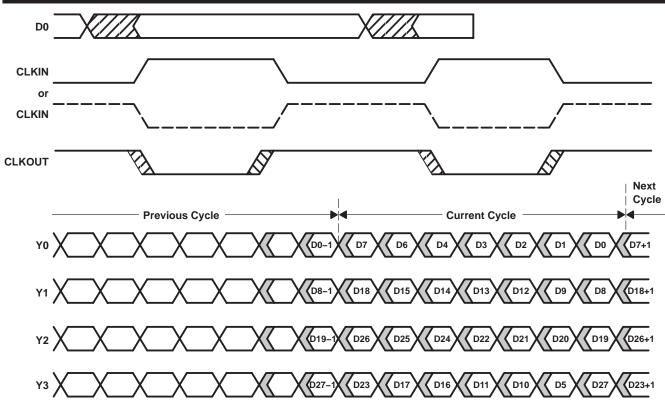
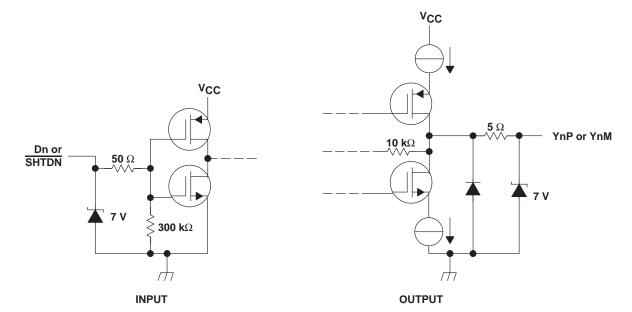


Figure 1. SN75LVDS83 Load and Shift Timing Sequences

equivalent input and output schematic diagrams





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### absolute maximum ratings over operating free-air temperature (unless otherwise noted)<sup>†</sup>

Supply voltage range, V <sub>CC</sub> (see Note 1)	–0.5 V to 4 V
Output voltage range, V <sub>O</sub> (all terminals)	–0.5 V to V <sub>CC</sub> + 0.5 V
Input voltage range, V <sub>I</sub> (all terminals)	–0.5 V to 5.5 V
Continuous total power dissipation	See Dissipation Rating Table
Storage temperature range, T <sub>stg</sub> Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to the GND terminals.

#### DISSIPATION RATING TABLE

PACKAGE	$T_A \le 25^{\circ}C$ POWER RATING	DERATING FACTOR <sup>‡</sup> ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING
DGG	1377 mW	11.0 mW/°C	822 mW

<sup>‡</sup> This is the inverse of the junction-to-ambient thermal resistance when board mounted and with no air flow.

### recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>	3	3.3	3.6	V
High-level input voltage, VIH	2			V
Low-level input voltage, VIL			0.8	V
Differential load impedance, ZL	90		132	Ω
Operating free-air temperature, T <sub>A</sub>	0		70	°C

#### timing requirements

		MIN	NOM M	٩X	UNIT
t <sub>C</sub>	Cycle time, input clock	14.7	32	2.3	ns
tw	Pulse duration, high-level input clock	0.4 t <sub>C</sub>	0.0	St <sub>C</sub>	ns
tt	Transition time, input signal			5	ns
t <sub>su</sub>	Setup time, data, D0 – D27 valid before CLKIN $\uparrow$ or CLKIN $\downarrow$ (see Figure 2)	3			ns
th	Hold time, data, D0 – D27 valid after CLKIN $\uparrow$ or CLKIN $\downarrow$ (see Figure 2)	1.5			ns



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## electrical characteristics over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	түр†	MAX	UNIT
VIT	Input threshold voltage			1.4		V
V <sub>OD</sub>	Differential steady-state output voltage magnitude		247		454	mV
$\Delta  V_{OD} $	Change in the steady-state differential output voltage magnitude between opposite binary states	$R_L = 100 \Omega$ , See Figure 3			50	mV
V <sub>OC(SS)</sub>	Steady-state common-mode output voltage		1.125		1.375	V
V <sub>OC</sub> (PP)	Peak-to-peak common-mode output voltage	See Figure 3			150	mV
ЧН	High-level input current	$V_{IH} = V_{CC}$			25	μA
١ <sub>IL</sub>	Low-level input current	$V_{IL} = 0$			±10	μΑ
		$V_{O(Yn)} = 0$			±24	mA
IOS	Short-circuit output current	$V_{OD} = 0$			±12	mA
I <sub>OZ</sub>	High-impedance state output current	$V_{O} = 0$ to $V_{CC}$			±10	μA
		Disabled, All inputs at GND			280	μA
Icc	Quiescent supply current	Enabled, $R_L = 100 \Omega$ , Gray-scale pattern (see Figure 4), $V_{CC} = 3.3 V$ , $t_c = 15.38 ns$		72	90	mA
		Enabled, $R_L = 100 \Omega$ , Worst-case pattern (see Figure 5), $t_C = 15.38 \text{ ns}$		85	110	mA
Cl	Input capacitance			3		pF

<sup>†</sup> All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C.



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### switching characteristics over recommended operating conditions (unless otherwise noted)

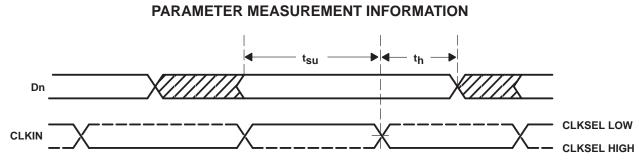
	PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
t <sub>d0</sub>	Delay time, CLKOUT <sup>↑</sup> to serial bit position 0		-0.2	0	0.2	ns
<sup>t</sup> d1	Delay time, CLKOUT $\uparrow$ to serial bit position 1		$\frac{1}{7}t_{C} - 0.2$		$\frac{1}{7}t_{C} + 0.2$	ns
t <sub>d2</sub>	Delay time, CLKOUT $\uparrow$ to serial bit position 2		$\frac{2}{7}t_{C}^{} - 0.2$		$\frac{2}{7}t_{c} + 0.2$	ns
td3	Delay time, CLKOUT <sup>↑</sup> to serial bit position 3	$t_c = 15.38 \text{ ns} (\pm 0.2\%),$  Input clock jitter  < 50 ps <sup>‡</sup> , See Figure 6	$\frac{3}{7}t_{C}^{} - 0.2$		$\frac{3}{7}t_{C} + 0.2$	ns
t <sub>d4</sub>	Delay time, CLKOUT <sup>↑</sup> to serial bit position 4	input clock jiller  < 50 ps+, See Figure 6	$\frac{4}{7}t_{C}^{} - 0.2$		$\frac{4}{7}t_{C} + 0.2$	ns
<sup>t</sup> d5	Delay time, CLKOUT <sup>↑</sup> to serial bit position 5		$\frac{5}{7}t_{C}^{} - 0.2$		$\frac{5}{7}t_{C} + 0.2$	ns
t <sub>d6</sub>	Delay time, CLKOUT <sup>↑</sup> to serial bit position 6		$\frac{6}{7}t_{C}^{} - 0.2$		$\frac{6}{7}t_{C} + 0.2$	ns
t <sub>sk(o)</sub>	Output skew, $t_n - \frac{n}{7}t_c$		-0.2		0.2	ns
<sup>t</sup> d7	Delay time, CLKIN $\downarrow$ to CLKOUT $\uparrow$	$t_{C} = 18.51 \text{ ns } (\pm 0.2\%),$  Input clock jitter  < 50 ps <sup>‡</sup> , See Figure 6	3.75	5.6	7.75	ns
	<b>6</b>	$t_{C}$ = 15.38 ± 0.75 sin (2 $\pi$ 500E3t) + 0.05 ns, See Figure 7		±70		ps
∆t <sub>c(o)</sub>	Cycle time, output clock jitter§	$t_{C}$ = 15.38 ± 0.75 sin (2 $\pi$ 3E6t) + 0.05 ns, See Figure 7		±187		ps
tw	Pulse duration, high-level output clock			$\frac{4}{7}t_{c}$		ns
t <sub>t</sub>	Transition time, differential output $(t_r \text{ or } t_f)$	See Figure 3	260	700	1500	ps
<sup>t</sup> en	Enable time, SHTDN↑ to phase lock (Yn valid)	See Figure 8		1		ms
<sup>t</sup> dis	Disable time, $\overline{\text{SHTDN}}\downarrow$ to off state (CLKOUT low)	See Figure 9		250		ns

<sup>†</sup> All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> =  $25^{\circ}$ C.

Input clock jitter is the magnitude of the change in the input clock period.
 Output clock jitter is the change in the output clock period from one cycle to the next cycle observed over 15000 cycles.

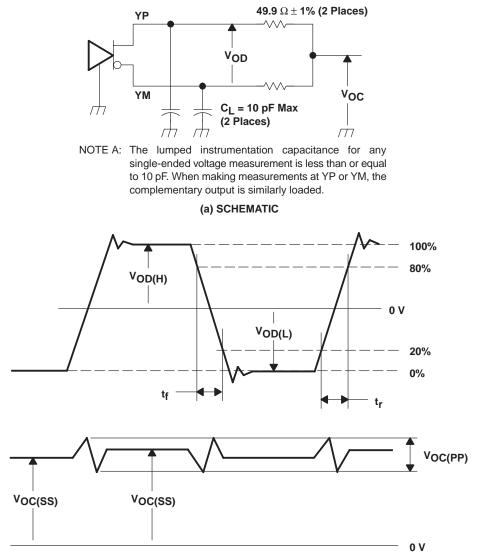


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NOTE A: All input timing is defined at 1.4 V on an input signal with a 10%-to-90% rise or fall time of less than 5 ns.

Figure 2. Setup and Hold Time Waveforms



(b) WAVEFORMS

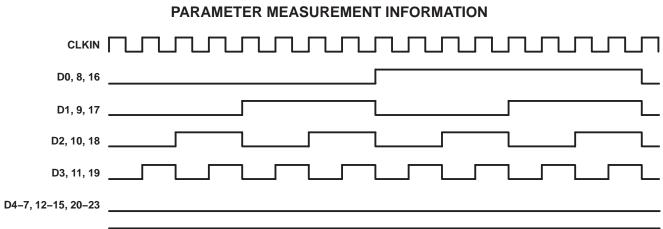
Figure 3. Test Load and Voltage Waveforms for LVDS Outputs



### Not Recommended for New Designs

## SN75LVDS83 FlatLink™ TRANSMITTER

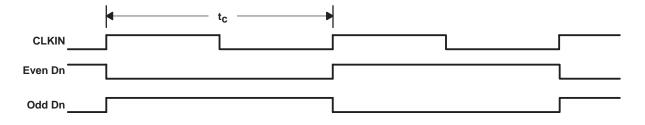
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D24-27

NOTE A: The 16-grayscale test-pattern test device power consumption for a typical display pattern. Pattern with CLKSEL low shown.

Figure 4. 16-Grayscale Test-Pattern Waveforms

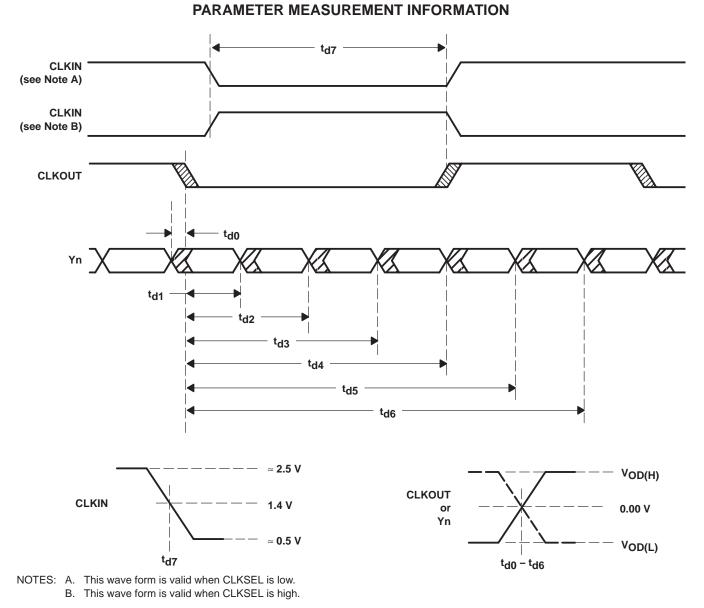


NOTE A: The worst-case test pattern produces nearly the maximum switching frequency for all of the LVDS outputs. Pattern with CLKSEL low shown.

Figure 5. Worst-Case Test-Pattern Waveforms



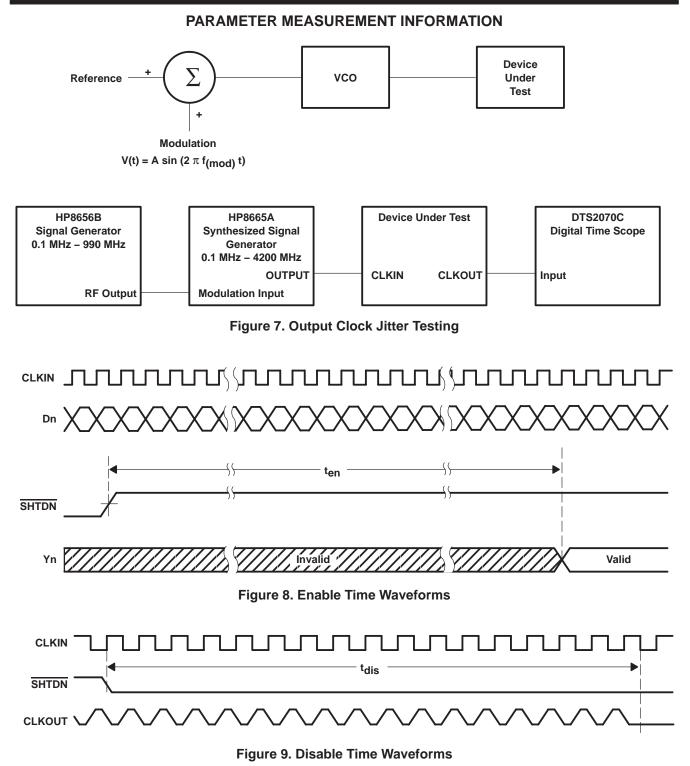
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#### Figure 6. SN75LVDS83 Timing Waveforms



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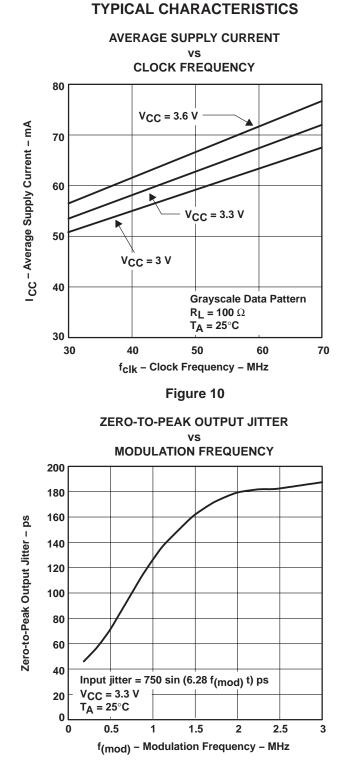
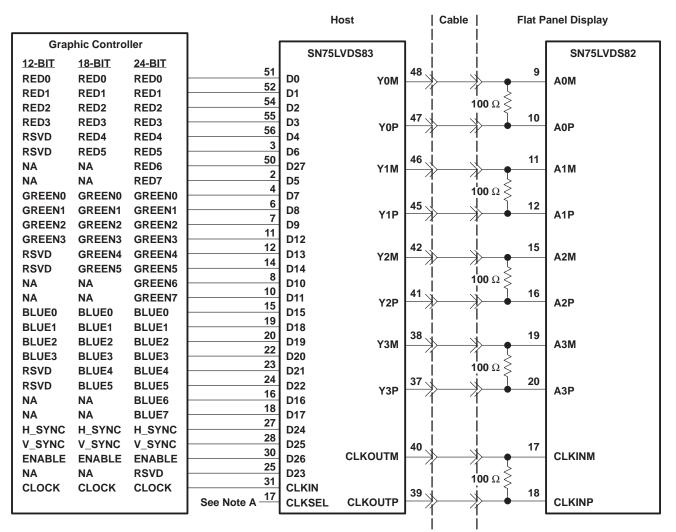


Figure 11



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APPLICATION INFORMATION

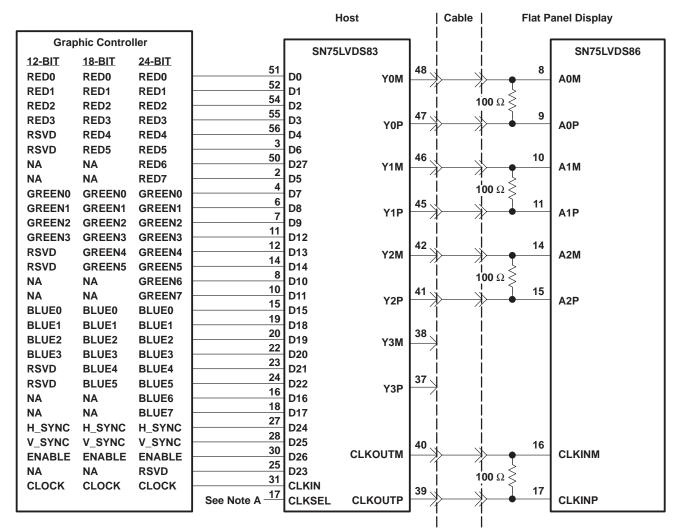


NOTES: A. Connect this terminal to  $V_{CC}$  for triggering to the rising edge of the input clock and to GND for the falling edge. B. The five 100- $\Omega$  terminating resistors are recommended to be 0603 types.

Figure 12. 24-Bit Color Host To 24-Bit LCD Panel Display Application



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### **APPLICATION INFORMATION**

NOTES: A. Connect this terminal to  $V_{CC}$  for triggering to the rising edge of the input clock and to GND for the falling edge. B. The four 100- $\Omega$  terminating resistors are recommended to be 0603 types.

Figure 13. 24-Bit Color Host To 18-Bit LCD Panel Display Application





1-May-2013

### PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing		Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings (4)	Samples
SN75LVDS83DGG	NRND	TSSOP	DGG	56	35	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	0 to 70	SN75LVDS83	
SN75LVDS83DGGG4	NRND	TSSOP	DGG	56	35	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	0 to 70	SN75LVDS83	
SN75LVDS83DGGR	NRND	TSSOP	DGG	56	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	0 to 70	SN75LVDS83	
SN75LVDS83DGGR-P	NRND	TSSOP	DGG	56		TBD	Call TI	Call TI			
SN75LVDS83DGGRG4	NRND	TSSOP	DGG	56	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	0 to 70	SN75LVDS83	
SN75LVDS83ZQL	NRND	BGA MICROSTAR JUNIOR	ZQL	56		TBD	Call TI	Call TI	-10 to 70		
SN75LVDS83ZQLR	NRND	BGA MICROSTAR JUNIOR	ZQL	52		TBD	Call TI	Call TI	-10 to 70		

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

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Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(3)</sup> MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.



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## PACKAGE OPTION ADDENDUM

1-May-2013

<sup>(4)</sup> Multiple Top-Side Markings will be inside parentheses. Only one Top-Side Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Top-Side Marking for that device.

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## PACKAGE MATERIALS INFORMATION

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### TAPE AND REEL INFORMATION

#### REEL DIMENSIONS

Texas Instruments





#### TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

## \*All dimensions are nominal

TAPE AND REEL INFORMATION

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN75LVDS83DGGR	TSSOP	DGG	56	2000	330.0	24.4	8.6	15.6	1.8	12.0	24.0	Q1

TEXAS INSTRUMENTS

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## PACKAGE MATERIALS INFORMATION

14-Jul-2012

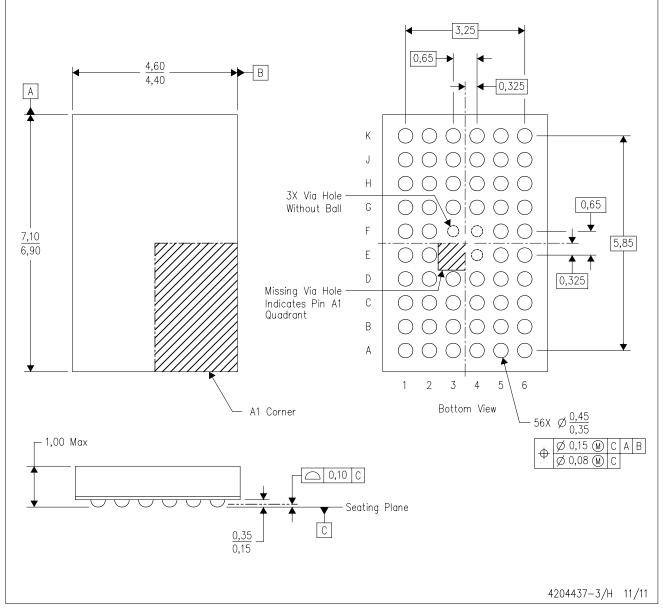


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN75LVDS83DGGR	TSSOP	DGG	56	2000	367.0	367.0	45.0

ZQL (R-PBGA-N56)

PLASTIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

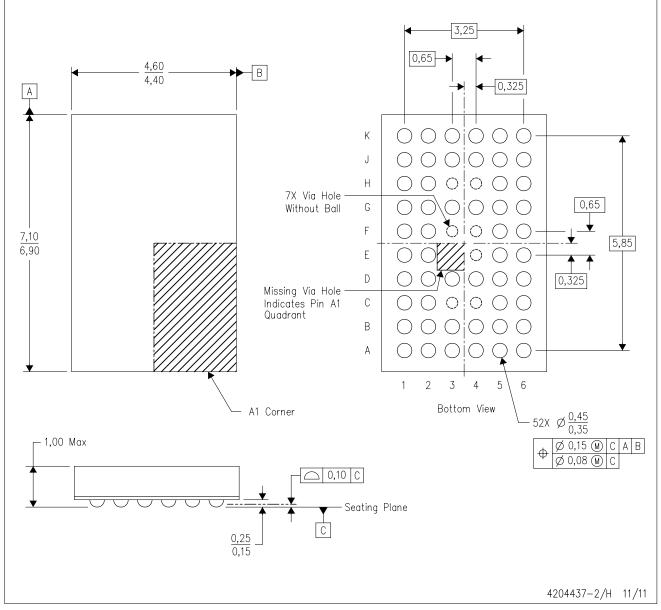
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- C. Falls within JEDEC MO-285 variation BA-2.
- D. This package is Pb-free. Refer to the 56 GQL package (drawing 4200583) for tin-lead (SnPb).

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ZQL (R-PBGA-N52)

PLASTIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MO-285 variation BA-2.
- D. This package is Pb-free. Refer to the 52 GQL package (drawing 4200583) for tin-lead (SnPb).

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## **MECHANICAL DATA**

MTSS003D - JANUARY 1995 - REVISED JANUARY 1998

#### DGG (R-PDSO-G\*\*)

### PLASTIC SMALL-OUTLINE PACKAGE

**48 PINS SHOWN** 



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold protrusion not to exceed 0,15.
- D. Falls within JEDEC MO-153



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